


<b>Search Notes</b>  	<b>Application/Control No.</b>  10522174	<b>Applicant(s)/Patent Under Reexamination</b>  AWANO ET AL.
	<b>Examiner</b>  Xiuyu Tai	<b>Art Unit</b>  1795

SEARCHED			
Class	Subclass	Date	Examiner
422	186.04	6/12/2008	xt

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search, assignee search, US-PGPUB, USPAT, USOCR, EPO, JPO, FPRS, DERWENT, GOOGLE	6/12/2008	xt

INTERFERENCE SEARCH			
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